

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION: JOHN T. BERRY, ET AL.

GROUP ART UNIT: 2857

SERIAL NUMBER: 10/825,181

EXAMINER: UNASSIGNED

FILED: APRIL 16, 2004

FOR: METHOD FOR DETERMINING SUPERFICIAL RESIDUAL STRESS AS APPLIED TO MACHINED, MECHANICALLY OR THERMALLY PROCESSED SURFACES



INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. 1.97

Assistant Commissioner for Patents
PO BOX 1450
ALEXANDRIA, VA 22313-1450

Sir:

Applicant(s) wish(es) to disclose the following information.

REFERENCES

- ☒ Applicant(s) wish(es) to make of record the documents listed on the attached Form PTO-1449. Copies of the listed documents are attached, where required, as are either statements of relevancy or any readily available full or partial English translations of any non-English-language documents.

RELATED CASES

- ☐ Attached is a list of Applicant's(s') pending applications and issued patents which may be related to the present application. Copies of the documents, where required, are attached along with Form PTO-1449.

CERTIFICATION

The undersigned certifies that

- ☐ each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign or international patent office in a counterpart foreign or international application for the first time (to the knowledge of the undersigned, having made reasonable inquiry) not more than three months prior to the filing of this statement.
- ☐ no item of information contained in this Information Disclosure Statement was cited in a communication from a foreign or international patent office in a counterpart foreign or international application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 C.F.R. 1.56(c) more than three months prior to the filing of this statement.

BASIS FOR CONSIDERATION

This Information Disclosure Statement is filed:

- ☐ without fee and within three months of the filing date of the application.
- ☐ without fee and within three months of the date of entry of the U.S. national stage.
- ☒ without fee and before the mailing date of a first Office Action on the merits (to the knowledge of the undersigned).
- ☐ without fee and with the appropriate certification above.
- ☐ without fee and with a new CPA application.
- ☐ without fee and with a Request for Continued Examination.
- ☐ with fee and before the mailing date of any Final Office Action, Notice of Allowance or an action that otherwise closes prosecution (to the knowledge of the undersigned).
- ☐ with fee, appropriate certification above, and before payment of the Issue Fee.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to Deposit Account No. 50-1442.

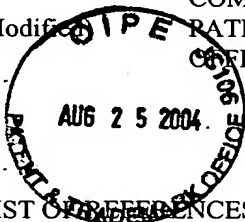
Respectfully submitted,

PIPER RUDNICK LLP

Steven B. Kelber
Attorney of Record
Registration No. 30,073

Perry E. Van Over
Registration No. 42,197

1200 Nineteenth Street, N.W.
Washington, DC 20036-2412
Telephone No. (202) 861-3900
Facsimile No. (202) 223-2085

Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT (Use Several Sheets if Necessary)		DOCKET NO. 2343-185-27 APPLICANT JOHN T. BERRY, ET AL. FILING DATE APRIL 16, 2004		SERIAL NO. 10/825,181 GROUP ART UNIT 2857			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO	
	AC						
	AD						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AE	Proffen, et al., Interactive Guide to Diffraction", http://www.uni-wuerzburg.de/mineralogie/crystal/teaching/teaching.html (2003).					
	AF	Simes, et al., "A Note on the Influence of Residual Stress on Measured Hardness, Research Note", Journal of Strain Analysis, 19(2):135-137 (1984).					
	AG	Tissue B.M., Chemistry Hypermedia Project, http://www.chem.vt.edu/chem-ed/diffraction/neutron.html (2000).					
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						
EXAMINER					DATE CONSIDERED		
*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							